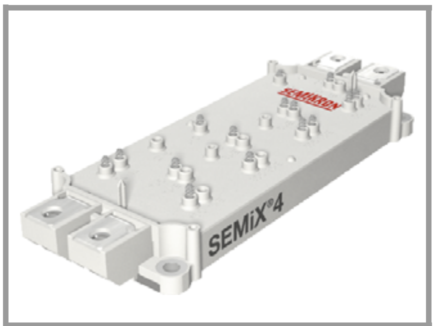


SEMiX®4s

Trench IGBT Modules

SEMiX604GB12E4s

Features

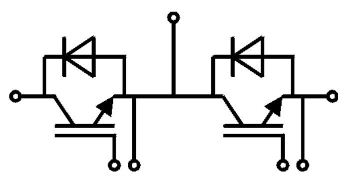
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognised file no. E63532

Typical Applications

- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to T_C=125°C max.
- Product reliability results are valid for T_j=150°C
- Dynamic values apply to the following combination of resistors:
  $R_{Gon,main}$ = 1,0 Ω
  $R_{Goff,main}$ = 6,2 Ω
  $R_{G,X}$ = 2,2 Ω
  $R_{E,X}$ = 0,5 Ω



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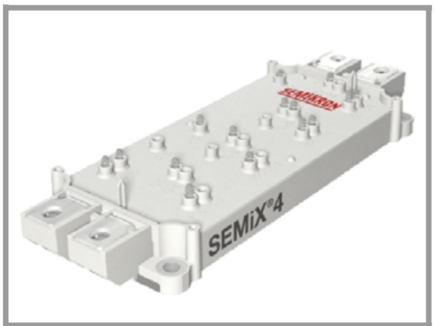
Absolute Maximum Ratings

Symbol	Conditions		Values	Unit
IGBT				
V_{CES}			1200	V
I_C	T_j = 175 °C	T_c = 25 °C	916	A
		T_c = 80 °C	704	A
I_{Cnom}			600	A
I_{CRM}	I_{CRM} = 3xI_{Cnom}		1800	A
V_{GES}			-20 ... 20	V
t_{psc}	V_{CC} = 800 V V_{GE} ≤ 20 V V_{CES} ≤ 1200 V	T_j = 150 °C	10	µs
T_j			-40 ... 175	°C
Inverse diode				
I_F	T_j = 175 °C	T_c = 25 °C	707	A
		T_c = 80 °C	529	A
I_{Fnom}			600	A
I_{FRM}	I_{FRM} = 3xI_{Fnom}		1800	A
I_{FSM}	t_p = 10 ms, sin 180°, T_j = 25 °C		3240	A
T_j			-40 ... 175	°C
Module				
$I_{t(RMS)}$			600	A
T_{stg}			-40 ... 125	°C
V_{isol}	AC sinus 50Hz, t = 1 min		4000	V

Characteristics

Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
$V_{CE(sat)}$	I_C = 600 A V_{GE} = 15 V chiplevel	T_j = 25 °C		1.8	2.05	V
		T_j = 150 °C		2.2	2.4	V
V_{CE0}		T_j = 25 °C		0.8	0.9	V
		T_j = 150 °C		0.7	0.8	V
r_{CE}	V_{GE} = 15 V	T_j = 25 °C		1.7	1.9	mΩ
		T_j = 150 °C		2.5	2.7	mΩ
$V_{GE(th)}$	V_{GE}=V_{CE}, I_C = 24 mA		5	5.8	6.5	V
I_{CES}	V_{GE} = 0 V V_{CE} = 1200 V	T_j = 25 °C		0.12	0.36	mA
		T_j = 150 °C				mA
C_{ies}	V_{CE} = 25 V V_{GE} = 0 V	f = 1 MHz		37.2		nF
C_{oes}		f = 1 MHz		2.32		nF
C_{res}		f = 1 MHz		2.04		nF
Q_G	V_{GE} = - 8 V...+ 15 V			3400		nC
R_{Gint}	T_j = 25 °C			1.25		Ω
$t_{d(on)}$	V_{CC} = 600 V I_C = 600 A $R_{G\,on}$ = 1.7 Ω $R_{G\,off}$ = 6.9 Ω di/dt$_{on}$ = 7100 A/µs di/dt$_{off}$ = 6350 A/µs	T_j = 150 °C		374		ns
t_r		T_j = 150 °C		85		ns
E_{on}		T_j = 150 °C		35		mJ
$t_{d(off)}$		T_j = 150 °C		1277		ns
t_f		T_j = 150 °C		114		ns
E_{off}		T_j = 150 °C		110.4		mJ
$R_{th(j-c)}$	per IGBT				0.049	K/W



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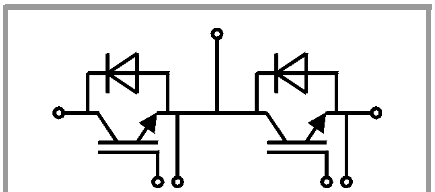

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Characteristics						
Symbol	**Conditions**		**min.**	**typ.**	**max.**	**Unit**
Inverse diode						
$V_F = V_{EC}$	I_F = 600 A V_{GE} = 0 V chip	T_j = 25 °C		2.1	2.46	V
		T_j = 150 °C		2.1	2.4	V
V_{F0}		T_j = 25 °C	1.1	1.3	1.5	V
		T_j = 150 °C	0.7	0.9	1.1	V
r_F		T_j = 25 °C	1.1	1.4	1.6	mΩ
		T_j = 150 °C	1.7	1.9	2.1	mΩ
I_{RRM}	I_F = 600 A di/dt_{off} = 6000 A/µs V_{GE} = -15 V V_{CC} = 600 V	T_j = 150 °C		430		A
Q_{rr}		T_j = 150 °C		100		µC
E_{rr}		T_j = 150 °C		44		mJ
$R_{th(j-c)}$	per diode				0.086	K/W
Module						
L_{CE}				22		nH
$R_{CC'+EE'}$	res., terminal-chip	T_C = 25 °C		0.7		mΩ
		T_C = 125 °C		1		mΩ
$R_{th(c-s)}$	per module			0.03		K/W
M_s	to heat sink (M5)		3		5	Nm
M_t		to terminals (M6)	2.5		5	Nm
						Nm
w					400	g
Temperatur Sensor						
R_{100}	T_c=100°C (R_{25}=5 kΩ)			493 ± 5%		Ω
$B_{100/125}$	$R_{(T)}=R_{100}exp[B_{100/125}(1/T-1/T_{100})]$; T[K];			3550 ±2%		K

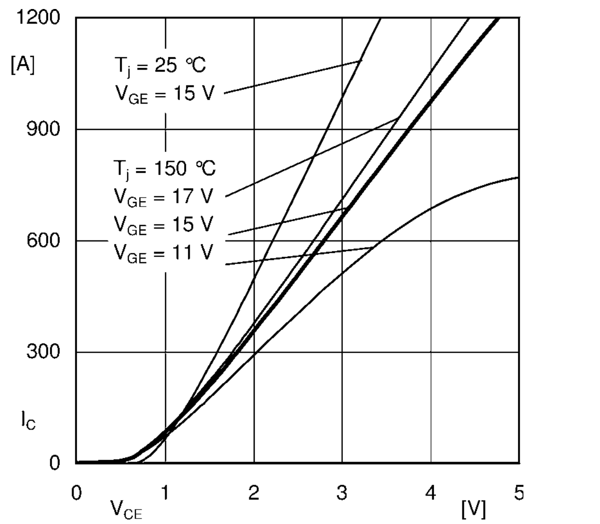


Fig. 1: Typ. output characteristic, inclusive $R_{CC'+ EE'}$

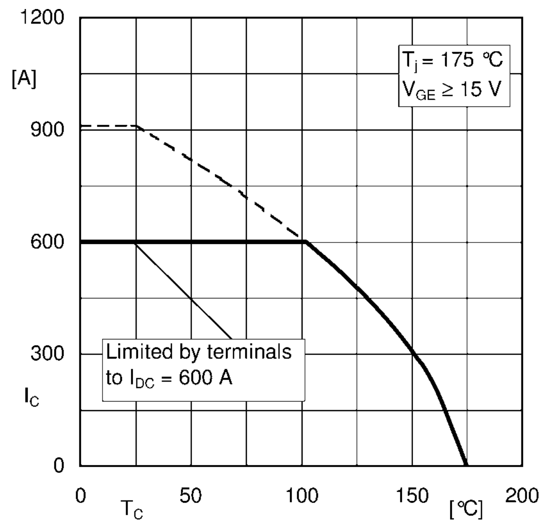


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

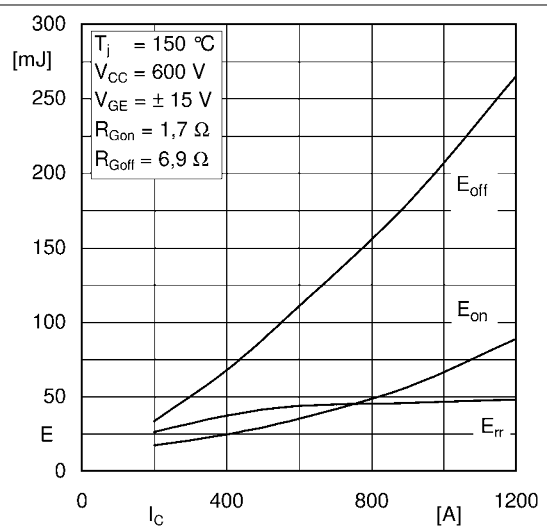


Fig. 3: Typ. turn-on /-off energy = f (I_C)

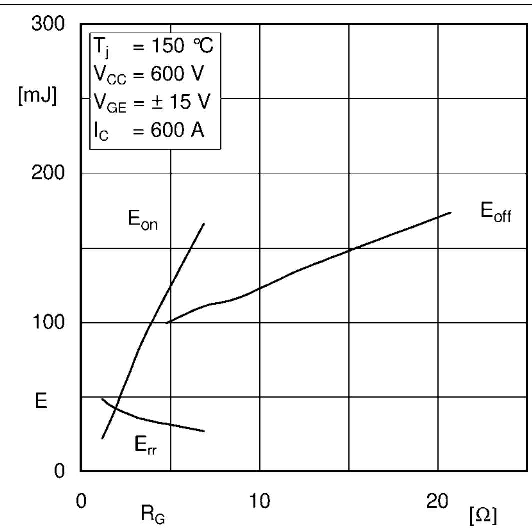


Fig. 4: Typ. turn-on /-off energy = f (R_G)

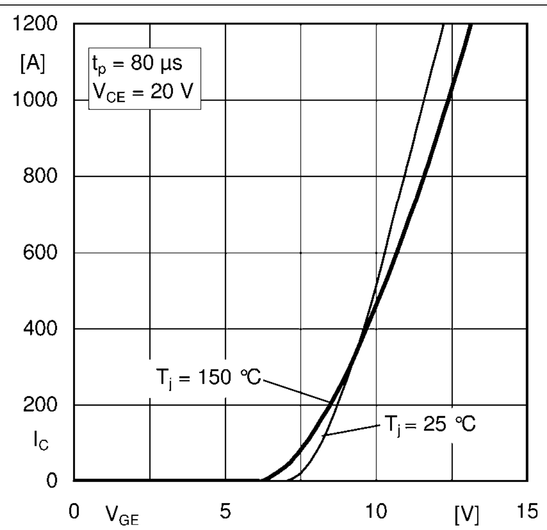


Fig. 5: Typ. transfer characteristic

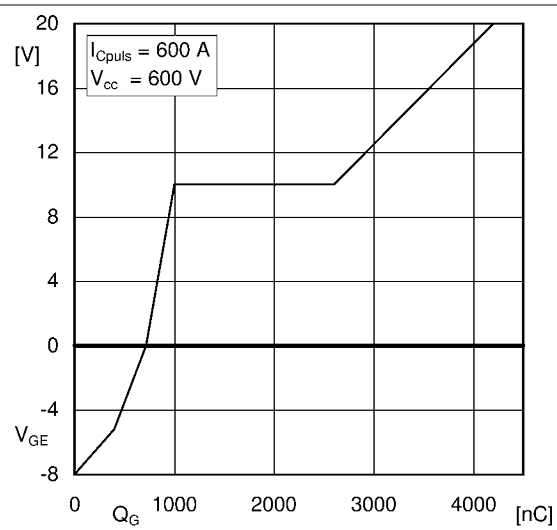


Fig. 6: Typ. gate charge characteristic

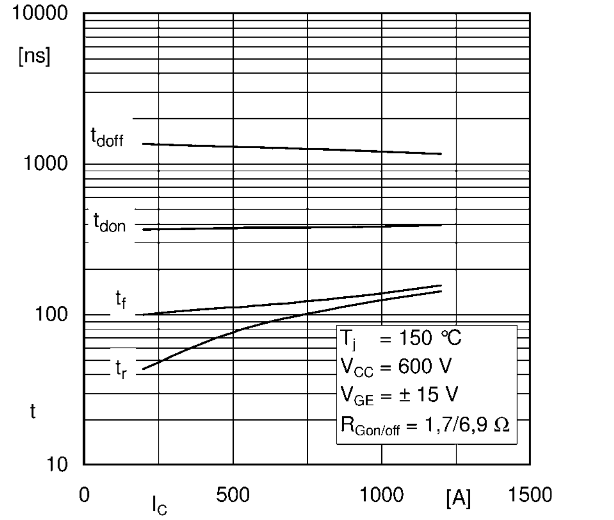


Fig. 7: Typ. switching times vs. I_C

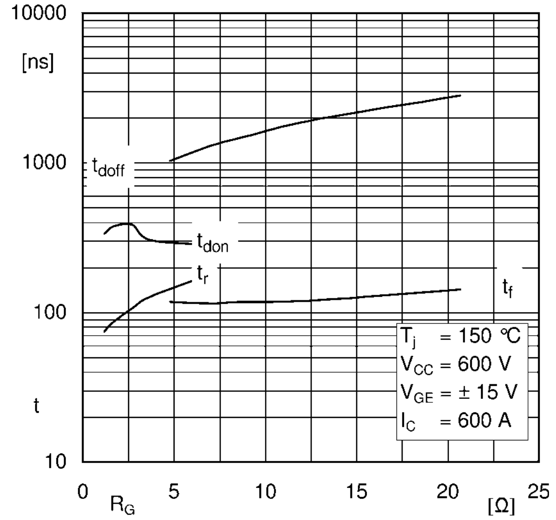


Fig. 8: Typ. switching times vs. gate resistor R_G

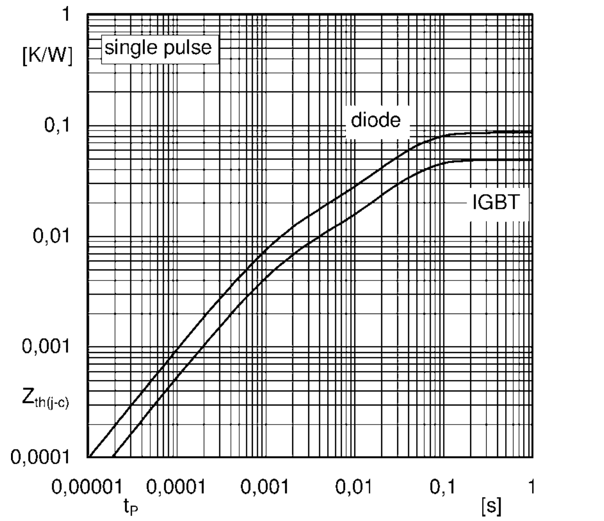


Fig. 9: Typ. transient thermal impedance

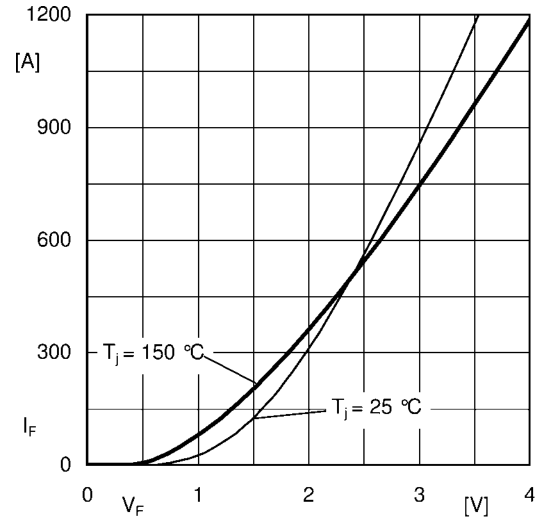


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC'+EE'}$

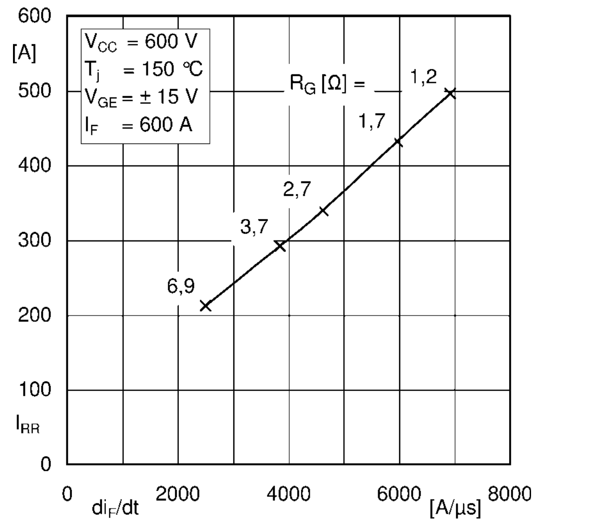


Fig. 11: Typ. CAL diode peak reverse recovery current

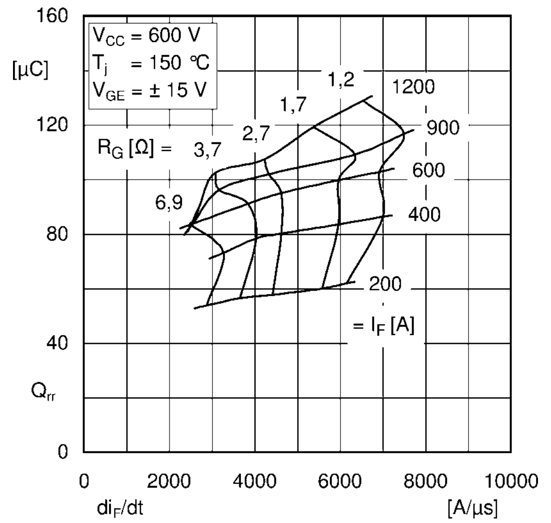
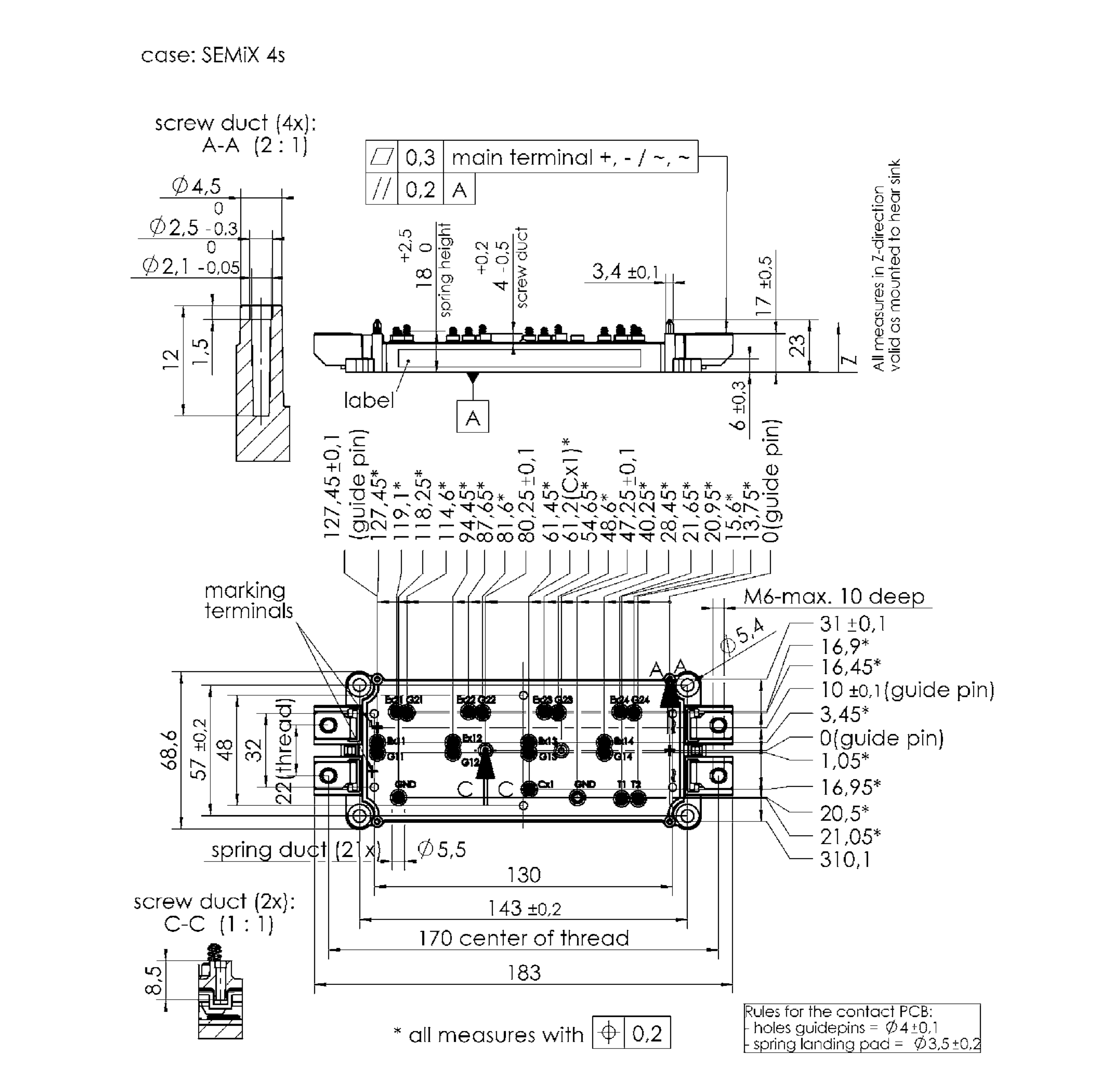
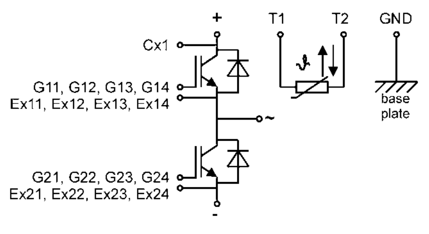


Fig. 12: Typ. CAL diode recovery charge



SEMiX 4s



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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

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